



Description

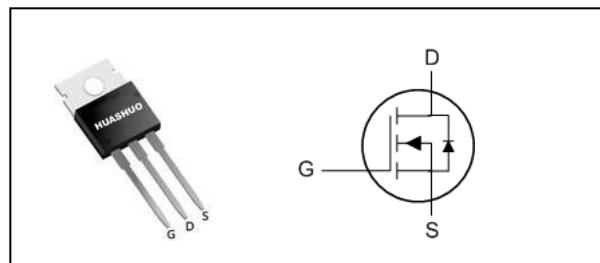
The HSF10N65 utilizes the advanced technology and low resistance package to achieve extremely low on-resistance device which makes the system design an efficient and reliable solution for use in a wide variety of applications.

- High Efficiency
- 100% EAS Guaranteed
- Improved dv/dt,di/dt capability
- Green Device

Product Summary

V _{DS}	650	V
R _{DS(ON),typ}	800	mΩ
I _D	10	A

TO220F Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	650	V
V _{GS}	Gate-Source Voltage	±30	V
I _D @T _c =25°C	Continuous Drain Current, V _{GS} @ 10V ₁	10	A
I _D @T _c =100°C	Continuous Drain Current, V _{GS} @ 10V ₁	6.5	A
I _{DM}	Pulsed Drain Current ²	40	A
EAS	Single Pulse Avalanche Energy ³	700	mJ
I _{AS}	Avalanche Current	16	A
P _D @T _c =25°C	Total Power Dissipation ⁴	48	W
T _{STG}	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-Ambient ₁	---	122	°C/W
R _{θJC}	Thermal Resistance Junction-Case ₁	---	2.6	°C/W



Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}$, $\text{I}_D=250\mu\text{A}$	650	---	---	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	BV_{DSS} Temperature Coefficient	Reference to 25°C , $\text{I}_D=1\text{mA}$	---	0.0193	---	$\text{V}/^\circ\text{C}$
$\text{R}_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$\text{V}_{\text{GS}}=10\text{V}$, $\text{I}_D=6.5\text{A}$	---	800	1000	$\text{m}\Omega$
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{GS}}=\text{V}_{\text{DS}}$, $\text{I}_D=250\mu\text{A}$	2	---	4	V
$\Delta \text{V}_{\text{GS}(\text{th})}$	$\text{V}_{\text{GS}(\text{th})}$ Temperature Coefficient		---	-3.97	---	$\text{mV}/^\circ\text{C}$
I_{DSS}	Drain-Source Leakage Current	$\text{V}_{\text{DS}}=650\text{V}$, $\text{V}_{\text{GS}}=0\text{V}$, $T_J=25^\circ\text{C}$	---	---	1	uA
		$\text{V}_{\text{DS}}=520\text{V}$, $\text{V}_{\text{GS}}=0\text{V}$, $T_J=125^\circ\text{C}$	---	---	100	
I_{GSS}	Gate-Source Leakage Current	$\text{V}_{\text{GS}}=\pm 30\text{V}$, $\text{V}_{\text{DS}}=0\text{V}$	---	---	± 100	nA
Q_g	Total Gate Charge (4.5V)	$\text{V}_{\text{DD}}=520\text{V}$, $\text{V}_{\text{GS}}=10\text{V}$, $\text{I}_D=10\text{A}$	---	32	---	nC
Q_{gs}	Gate-Source Charge		---	6.3	---	
Q_{gd}	Gate-Drain Charge		---	10	---	
$\text{T}_{\text{d}(\text{on})}$	Turn-On Delay Time	$\text{V}_{\text{DD}}=325\text{V}$, $\text{V}_{\text{GS}}=10\text{V}$, $\text{R}_g=10\Omega$	---	60	---	ns
T_r	Rise Time		---	103	---	
$\text{T}_{\text{d}(\text{off})}$	Turn-Off Delay Time		---	200	---	
T_f	Fall Time		---	77	---	
C_{iss}	Input Capacitance	$\text{V}_{\text{DS}}=25\text{V}$, $\text{V}_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	1310	---	pF
C_{oss}	Output Capacitance		---	140	---	
C_{rss}	Reverse Transfer Capacitance		---	20	---	

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,5}	$\text{V}_{\text{G}}=\text{V}_{\text{D}}=0\text{V}$, Force Current	---	---	10	A
I_{SM}	Pulsed Source Current ^{2,5}		---	---	40	A
V_{SD}	Diode Forward Voltage ²	$\text{V}_{\text{GS}}=0\text{V}$, $\text{I}_s=1\text{A}$, $T_J=25^\circ\text{C}$	---	---	1.4	V
t_{rr}	Reverse Recovery Time	$\text{I}_{\text{F}}=10\text{A}$, $d\text{I}/dt=100\text{A}/\mu\text{s}$, $T_J=25^\circ\text{C}$	---	470	---	ns
Q_{rr}	Reverse Recovery Charge		---	4.8	---	nC

Note : 4. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$

5. Essentially independent of operating temperature



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Typical Characteristics

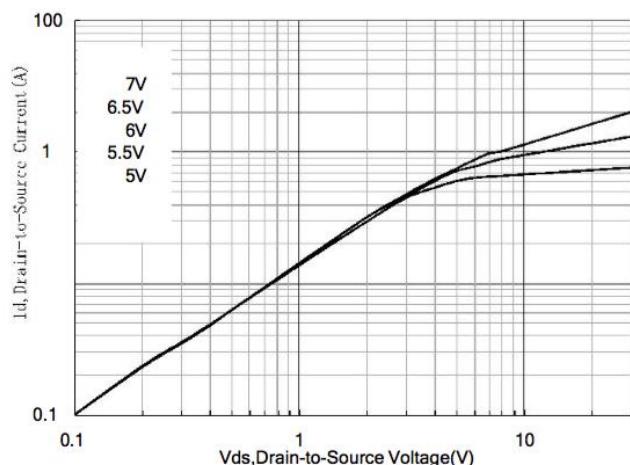


Figure 1.Typical Output Characteristics

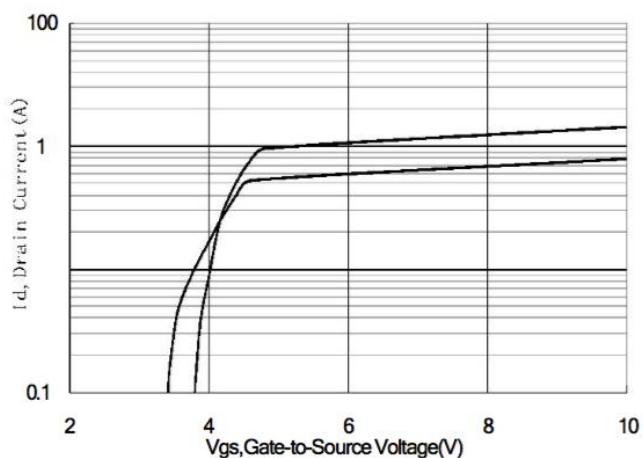


Figure2.Typical Transfer Characteristics

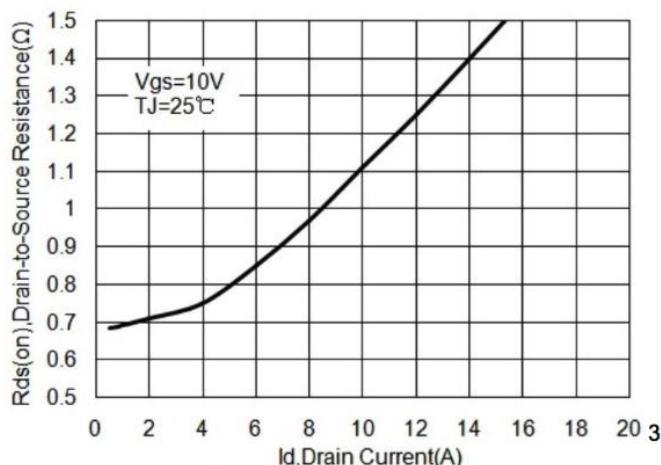


Figure 3.On-Resistance versus Drain Current

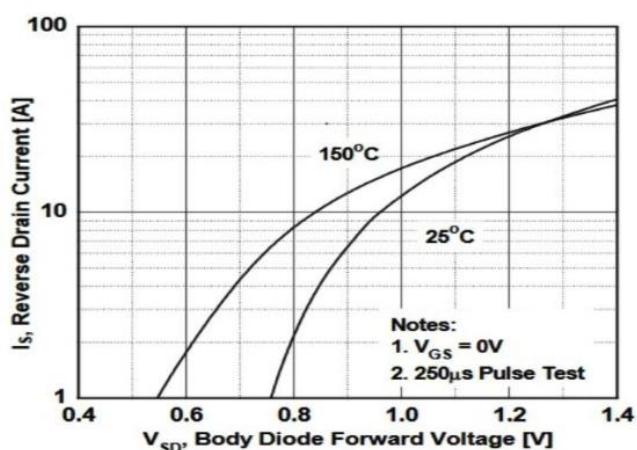


Figure4.Diode ForwardVoltage versus Current

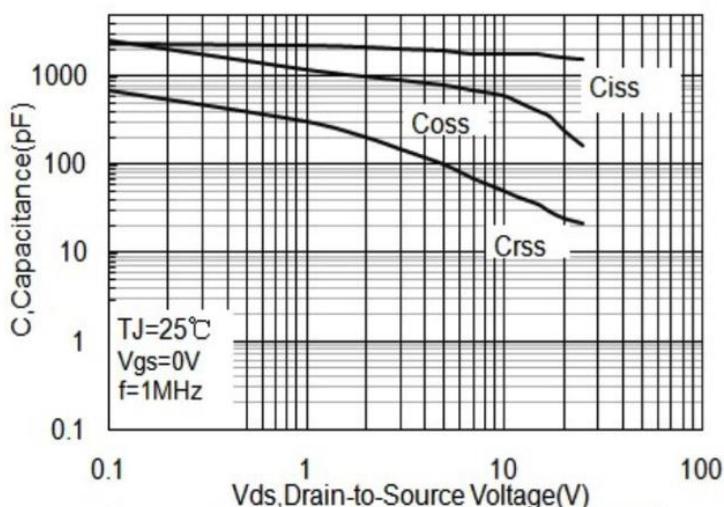


Figure 5.Typical Capacitance vs.Drian-to-Source Voltage

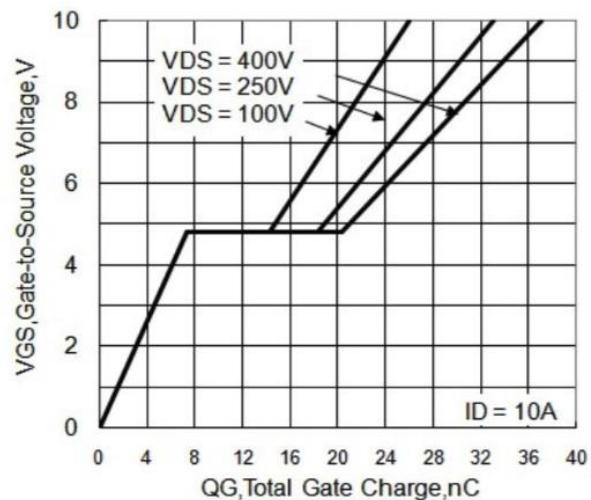


Figure 6.Typical Gate Charge vs.Vgs



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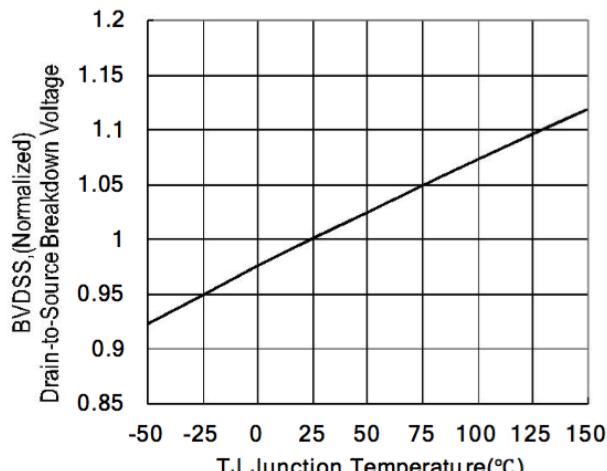


Figure 7.Bvdss Variation with Temperature

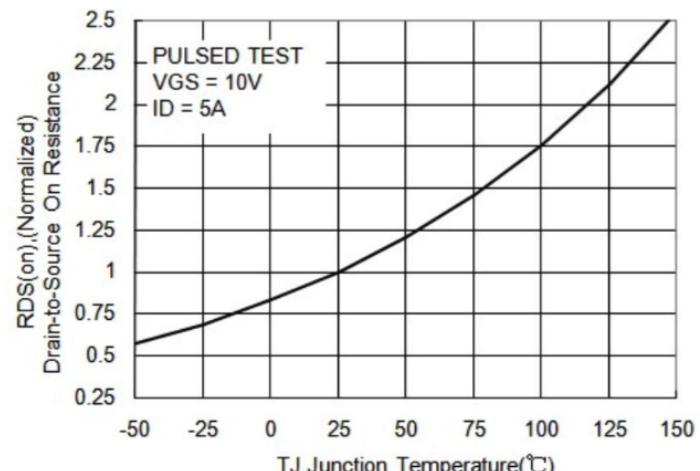


Figure 8.On-Resistance Variation with Temperature

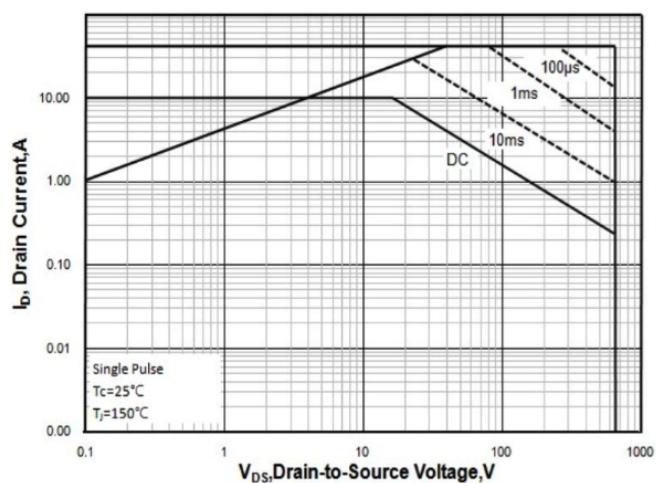


Figure 9. Maximum Safe Operating Area

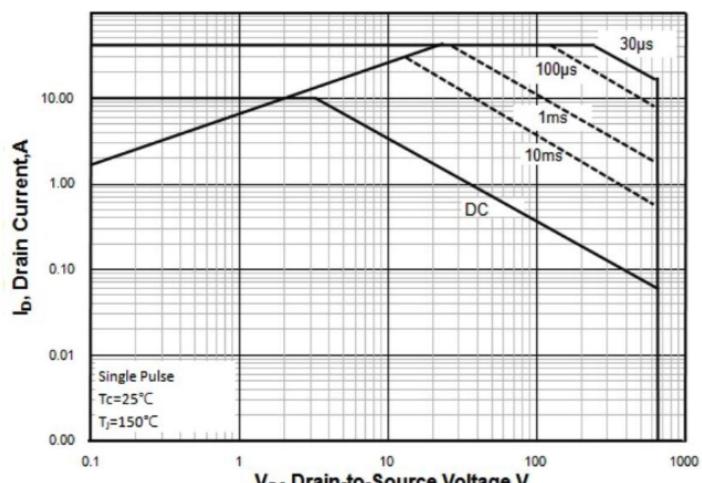


Figure 9. Maximum Safe Operating Area

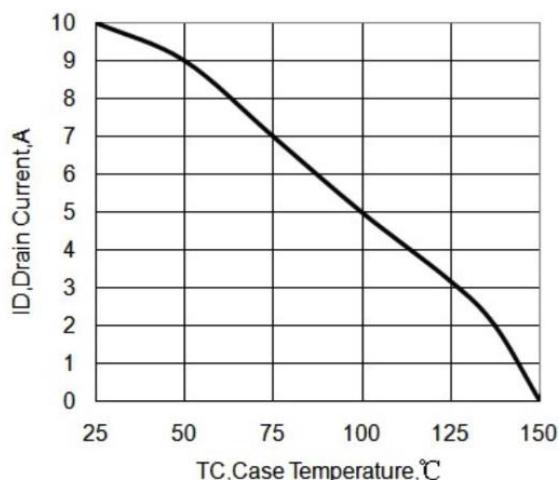
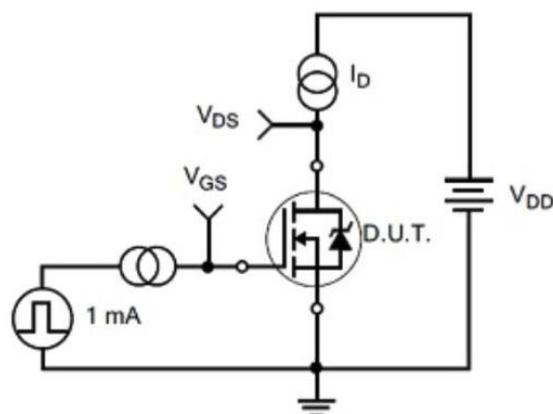


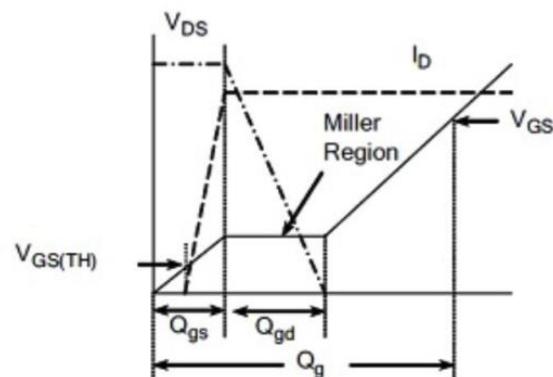
Figure 10. Maximum Continuous Drain Current vs Case Temperature



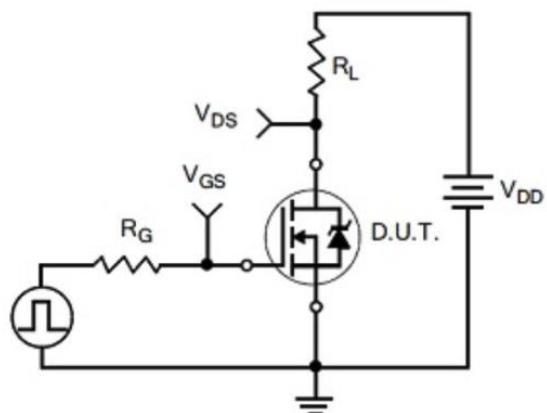
TEST CIRCUITS AND WAVEFORMS



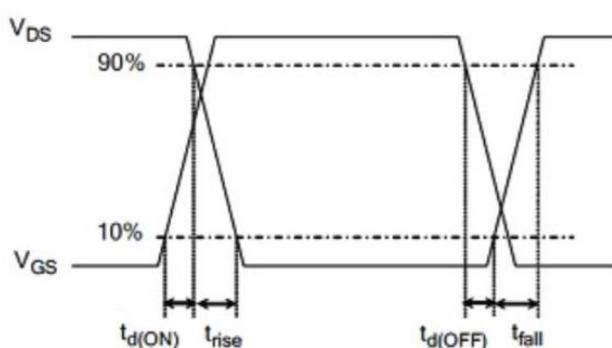
Gate Charge Test Circuit



Gate Charge Waveform



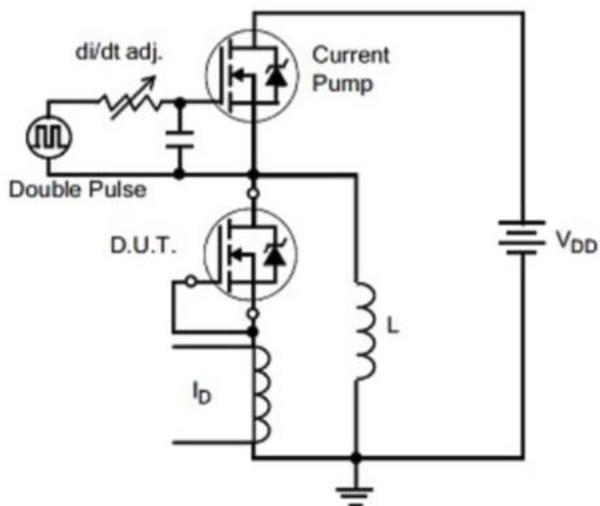
Resistive Switching Test Circuit



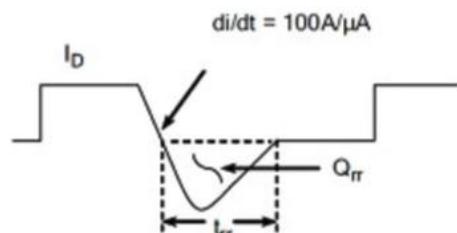
Resistive Switching Waveforms



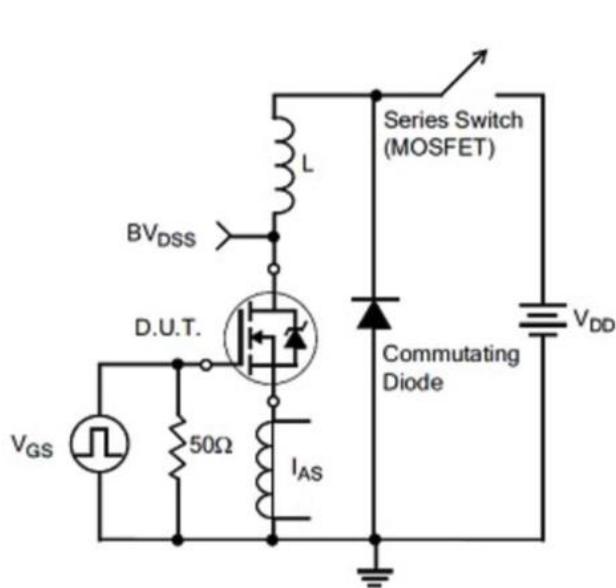
TEST CIRCUITS AND WAVEFORMS(Cont.)



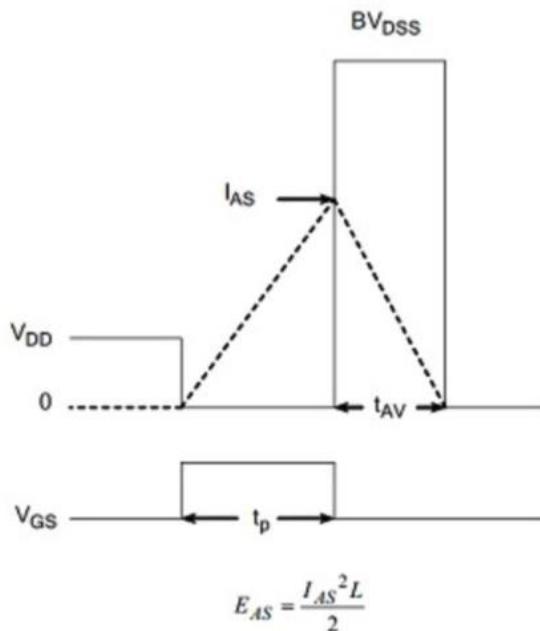
Diode Reverse Recovery Test Circuit



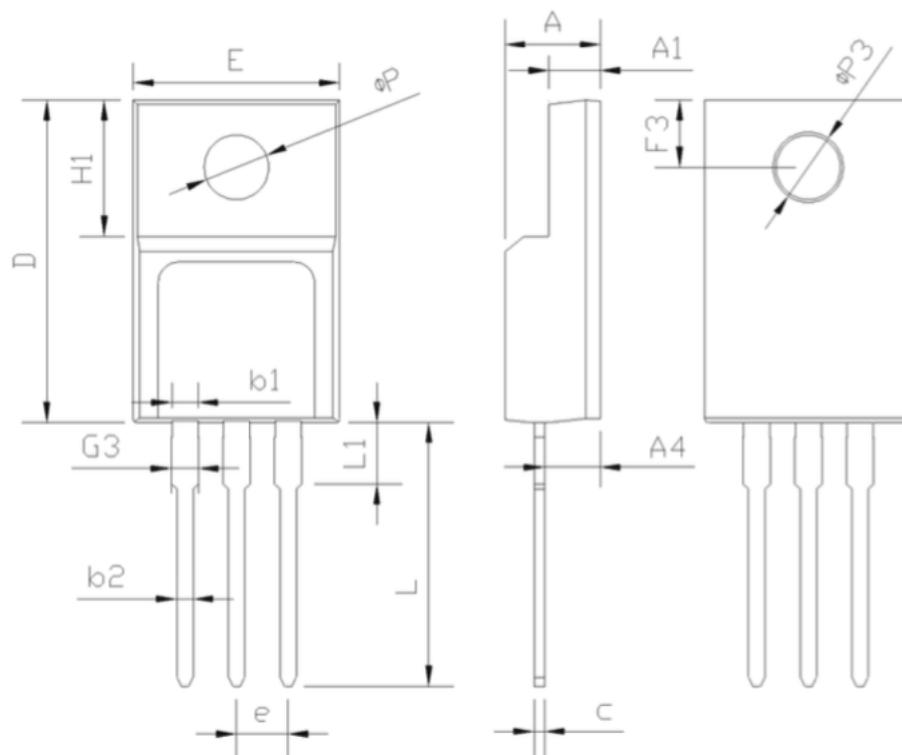
Diode Reverse Recovery Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms



SYMBOL	mm		
	MIN	NOM	MAX
E	9.96	10.16	10.36
A	4.50	4.70	4.90
A1	2.34	2.54	2.74
A4	2.56	2.76	2.96
c	0.40	0.50	0.65
D	15.57	15.87	16.17
H1	6.70REF		
e	2.54BSC		
L	12.68	12.98	13.28
L1	2.88	3.03	3.18
ΦP	3.03	3.18	3.38
ΦP3	3.15	3.45	3.65
F3	3.15	3.30	3.45
G3	1.25	1.35	1.55
b1	1.18	1.28	1.43
b2	0.70	0.80	0.95